

Investigation of Atomic Layer Deposition for Distributed Bragg Reflector Mirror Stack

*Jonathan Chandonait¹, Shyam Bharadwaj²,
Kevin Lee², SM (Moudud) Islam², Debdeep
Jena^{2,3} and Huili (Grace) Xing^{2,3}*

¹*Colleges of Nanoscale Science and Engineering, SUNY Polytechnic Institute, 257 Fuller Road, Albany, NY 12203, United States*

²*School of Electrical and Computer Engineering, Cornell University, Duffield Hall, Ithaca, NY 14853, United States*

³*Department of Materials Science and Engineering, Cornell University, Bard Hall, Ithaca, NY 14853, United States*

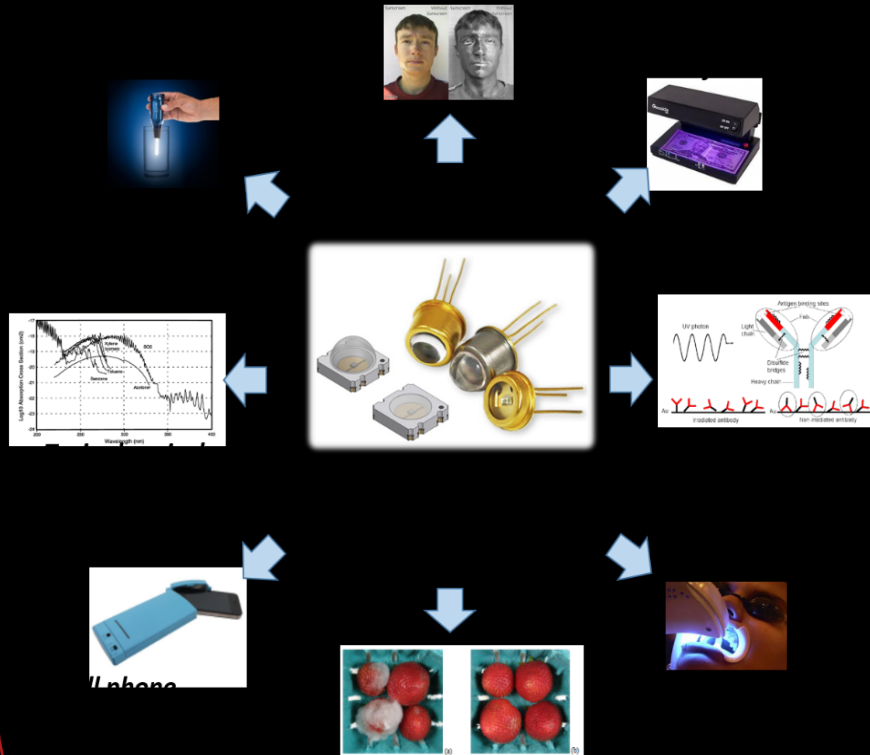


Cornell
University



DUV LEDs

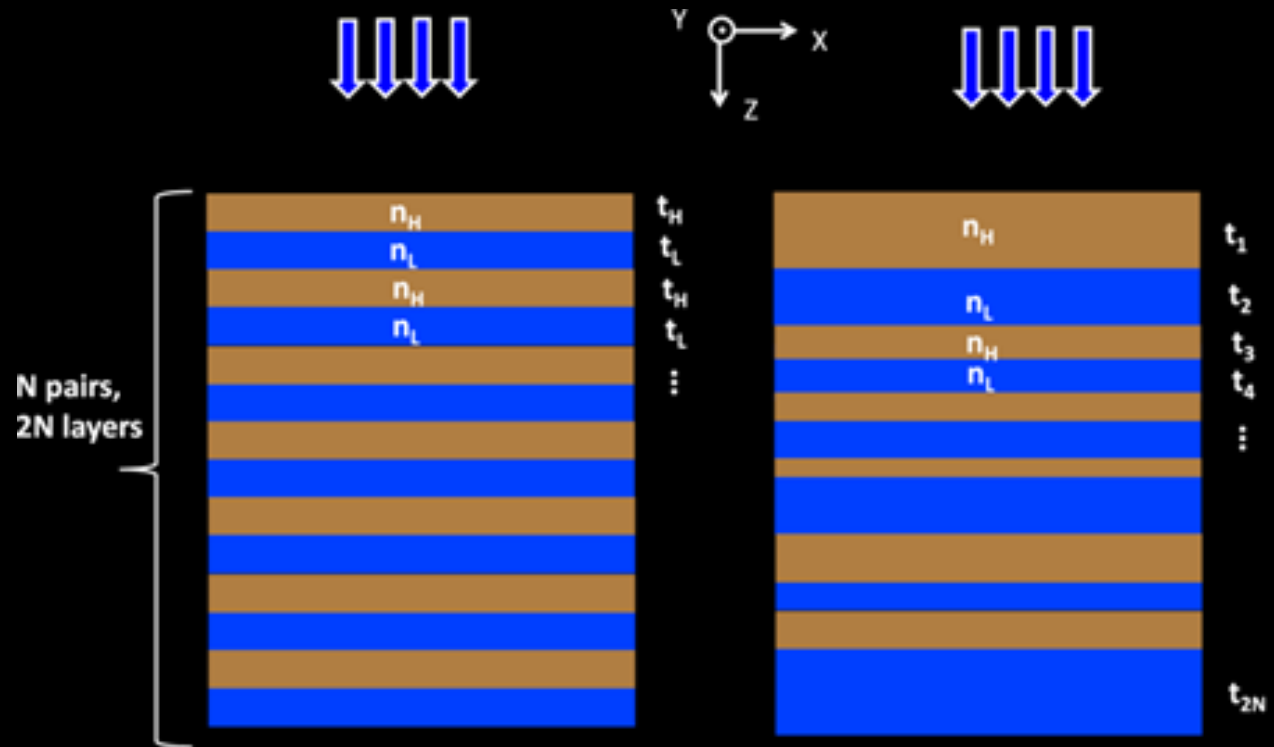
Applications



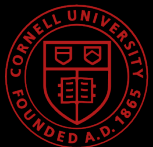
- Higher Energy, Small Wavelength
- Ability to damage DNA

Distributed Bragg Reflector

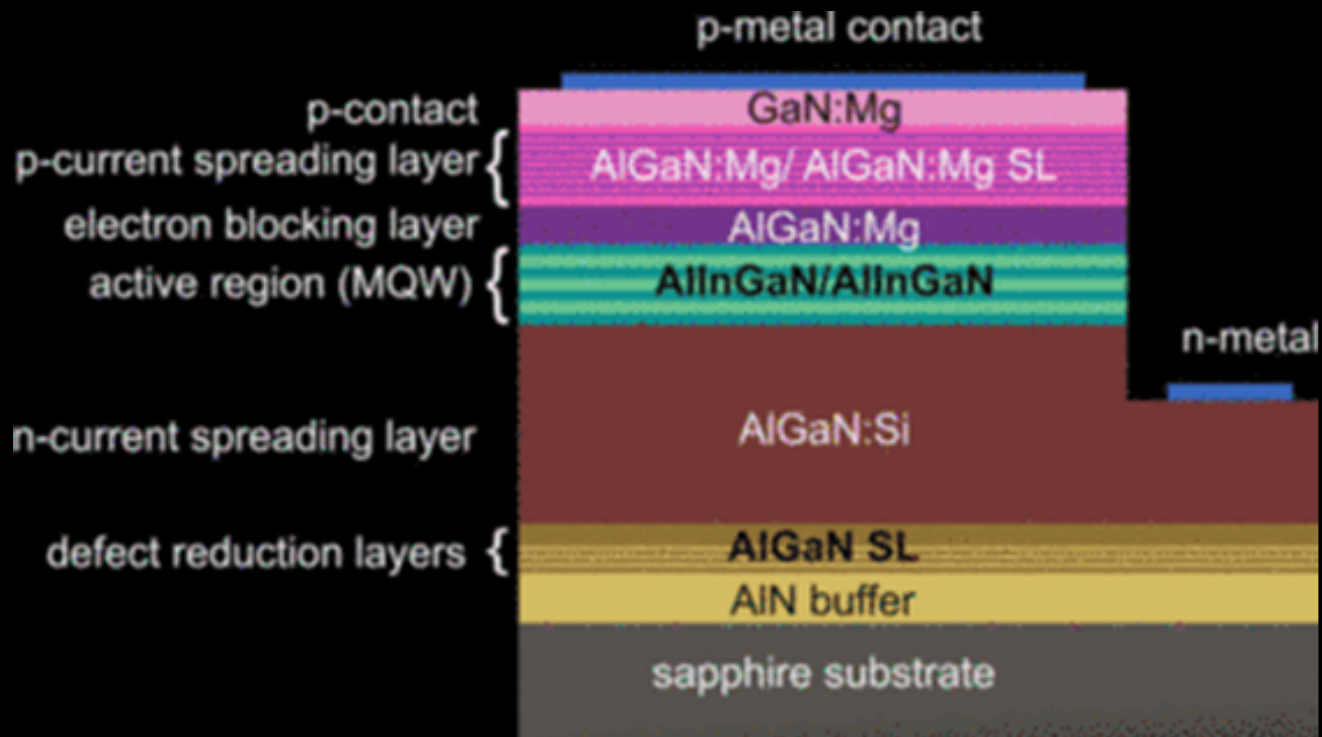
- Alternating Layers of High and Low Indexes of Refraction
- High Bandwidth to avoid Absorption
- $\frac{1}{4} \lambda$ Layer Thickness to promote constructive interference



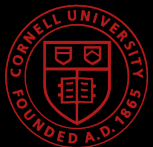
https://www.researchgate.net/figure/280063325_fig8_Periodic-and-aperiodic-distributed-Bragg-reflector-DBR-stacking-n_H-and-t_H



DUV LED Structure

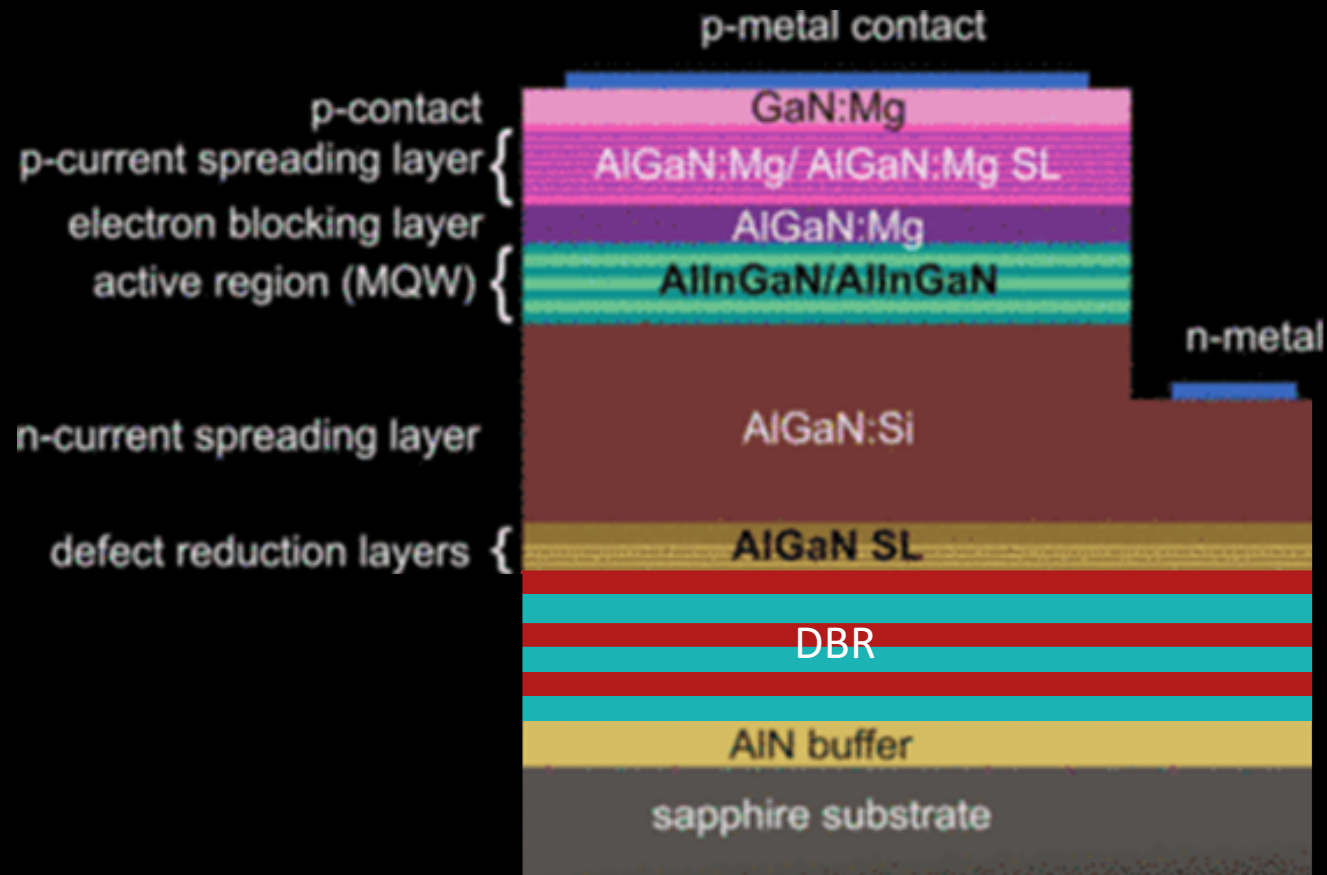


<http://www.laytec.de/uvled>

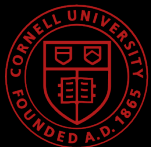


Cornell University
Cornell NanoScale Science
and Technology Facility

DUV LED Structure

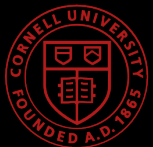


<http://www.laytec.de/uvled>



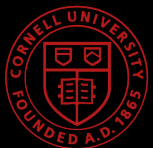
DBR Problems

- Crystal Lattice Match
- Indexes of Refraction
- Material Bandgap
- Layer Strain
- Crystal Quality
- UltrasMOOTH Surface
- Layer Profiles
- Process Compatibility



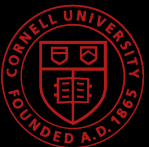
Methods

- Molecular Beam Epitaxy (MBE) [Most Common]
- Chemical Vapor Deposition (CVD)
- Metalorganic Vapor Phase Epitaxy (MOVPE)
- Atomic Layer Deposition (ALD)



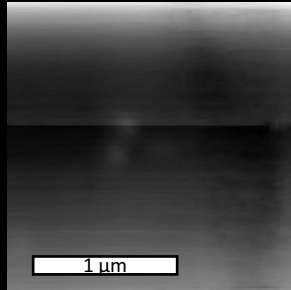
Goal

- Explore viability of ALD has a method of building DBRs for DUV LEDs

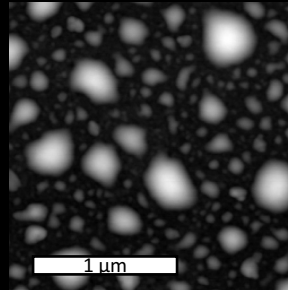


Ultrasmooth Surfaces

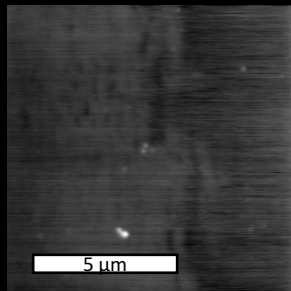
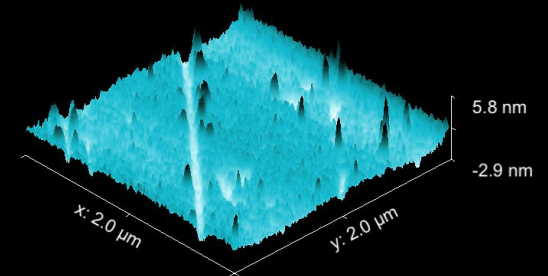
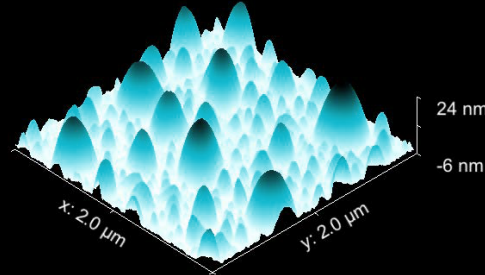
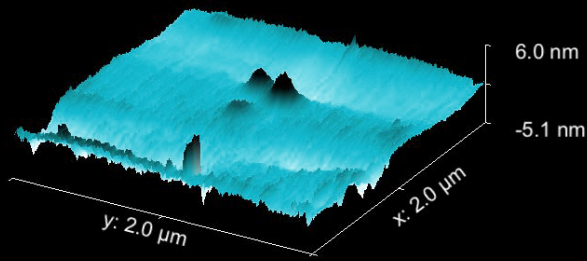
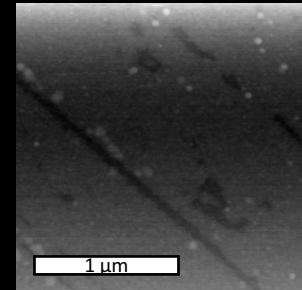
Al_2O_3 300°C



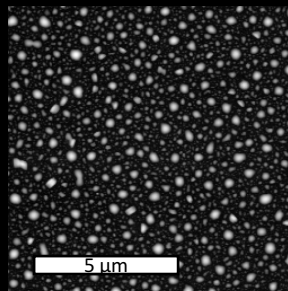
AlN 300°C



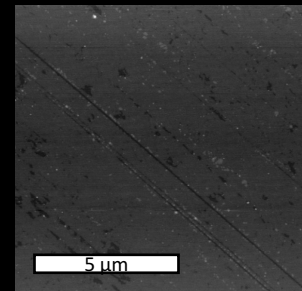
Ta_2O_5 300°C



0.7nm RMS
Roughness



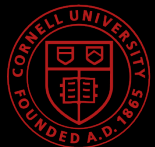
1.0nm RMS
Roughness



0.1nm RMS
Roughness

Growth Time

Growth Technique	MBE	ALD
Growth Rate of ALN (nm/hour)	200	20



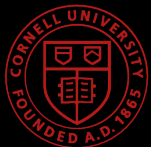
ALD Crystal Quality

- Hard to match crystal structure
- Considered poor relative crystal quality
- Amorphous



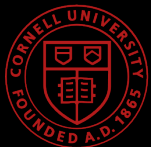
Pros

- ✓ Ultrasmooth surfaces
- ✓ Highly precise thickness accuracy
- ✓ Substrate compatibility
- ✓ New type of materials
- ✓ Low Temperature
- ✓ High Conformity



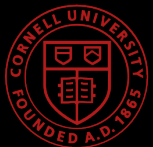
Cons

- Very Slow
- Relatively Poor Crystal
- Lattice Matching Problems



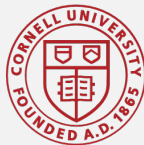
Conclusions

- ALD has potential to be used for DBRs in some cases but faces many obstacles to be viable.



Acknowledgements

- National Science Foundation
- National Nanotechnology Coordinated Infrastructure
- Cornell NanoScale Science & Technology Facility
 - NSF grant no. ECCS-1542081
- Dr. Grace Xing
- Shyam Bharadwaj, Moudud Islam
- CNF REU Program Coordinators
- CNF Staff



Cornell
University

